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Complex impedance scanning tunneling microscopy: a novel probe to study (un)conventional (super)conductivity

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Citation

Mozes, A. (2026, June 17). *Complex impedance scanning tunneling microscopy: a novel probe to study (un)conventional (super)conductivity*. Retrieved from <https://hdl.handle.net/1887/4306631>

Version: Publisher's Version

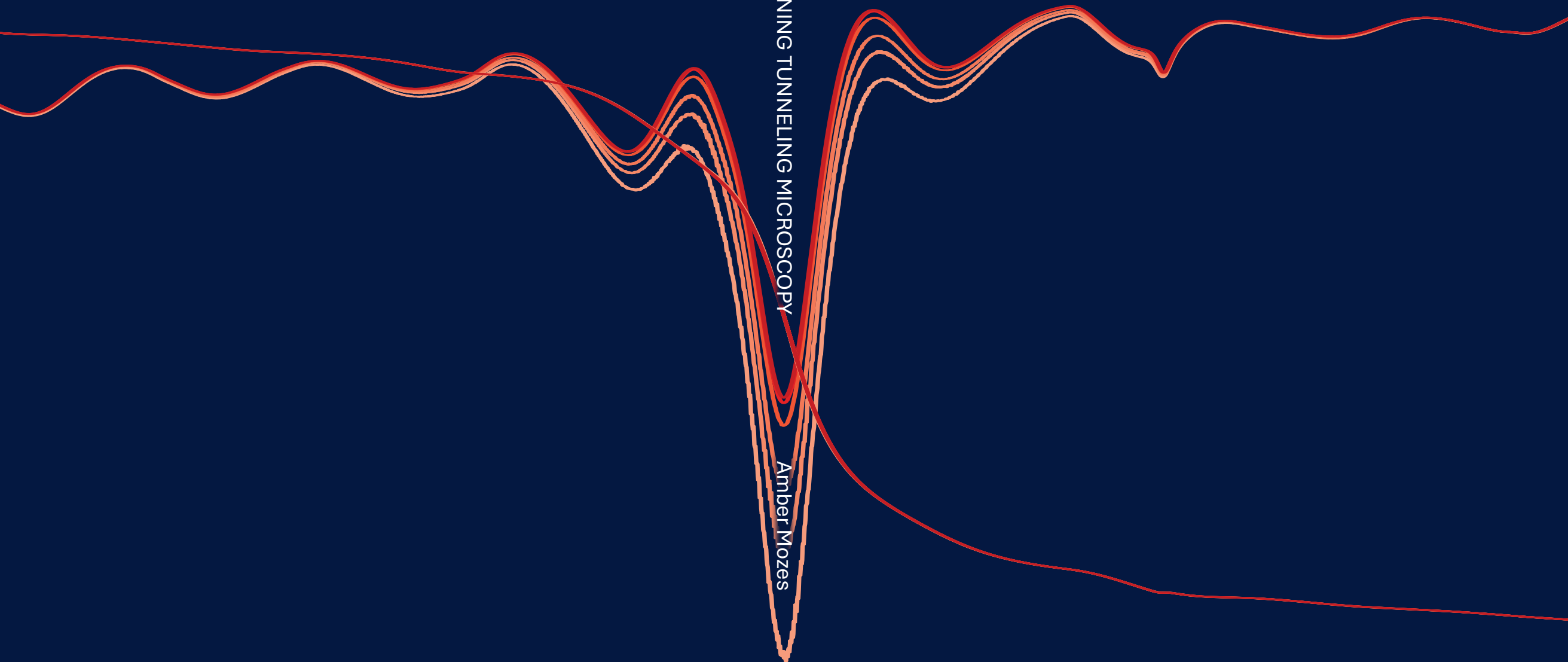
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COMPLEX IMPEDANCE SCANNING TUNNELING MICROSCOPY

A novel probe to study (un)conventional (super)conductivity



COMPLEX IMPEDANCE SCANNING TUNNELING MICROSCOPY

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2026

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